

**TranElectric**

**IRFCF30  
Die for Hexfet®**

## Die Specification

### General description :

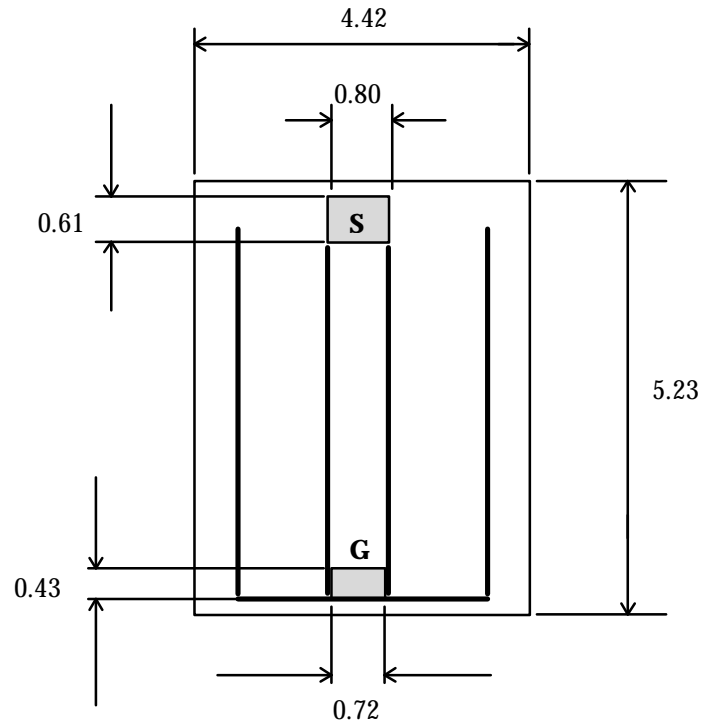
Hexfet® power MOSFET die with the following features:

- \* **Dynamic dv/dt rating**
- \* **Ease of paralleling**
- \* **Repetitive avalanche rated**
- \* **Fast switching**

### Mechanical Characteristic:

Silicon Chip

Dimension (mm):	4.42*5.32
Dimension (mil):	174*206
Thickness:	
Metallization:	Al
Recommended wire(mm):	0.25
Recommended wire(mil):	10



Type	Vds	Rds(on) Vgs=10V	Idss @Ids	Vgs(th) Vds=Vgs, Id=250mkA
IRFCF30	900V	3.70 Ohms	250 mA	2.0V ... 4.0V

Typical device : IRFBF30 (in TO-220AB)

**Absolut Maximum Rating**

	Parameter	Max.	Units
$I_D$ , $T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS}=10\text{V}$	3.6	A
$I_D$ , $T_C=100^\circ\text{C}$	Continuous Drain Current $V_{GS}=10\text{V}$	2.3	
$I_{DM}$	Pulsed Drain Current ❶	14	
$P_D$ , $T_C=25^\circ\text{C}$	Power Dissipation	125	W
	Linear Derating Factor	1.0	W/ $^\circ\text{C}$
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
EAS	Single Pulse Avalanche Energy ❷	250	mJ
IAR	Avalanche Current	3.6	A
EAR	Repetitive Avalanche Energy ❶	13	mJ
dv/dt	Peak Diode Recovery dv/dt ❸	1.5	V/ns
$T_J$ , $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

**Electrical Characteristics,  $T_J=25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	900			V	$V_{GS}=0$ , $I_D=250\mu\text{A}$
$\Delta V_{(BR)}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		1.1		V/ $^\circ\text{C}$	$25^\circ\text{C}$ , $I_D=1\text{mA}$
$R_{(DS)on}$	Static Drain-to-Source On-Resistance			3.7	$\Omega$	$V_{GS}=10\text{V}$ , $I_D=2.2\text{A}$ ❹
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$
$g_{fs}$	Forward Transconductance	2.3			S	$V_{DS}=100\text{V}$ , $I_D=2.2\text{A}$
$I_{DSS}$	Drain-to-Source Leakage Current			100	$\mu\text{A}$	$V_{DS}=900\text{V}$ , $V_{GS}=0\text{V}$
				500	$\mu\text{A}$	$V_{DS}=720\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Current			100	nA	$V_{GS}=20\text{V}$
	Gate-to-Source Reverse Current			-100	nA	$V_{GS}=-20\text{V}$
$Q_g$	Total Gate Charge			78	nC	$V_{GS}=10\text{V}$
$Q_{gs}$	Gate-to-Source Charge			10	nC	$V_{DS}=360\text{V}$
$Q_{gd}$	Gate-to-Drain Charge			42	nC	$I_D=3.6\text{A}$ ❹
$t_{d(on)}$	Turn-On Delay Time		14		ns	$V_{DD}=450\text{V}$ $I_D=3.6\text{A}$ $R_G=12\Omega$ $R_D=120\Omega$ ❹
$t_r$	Rise Time		25			
$t_{d(off)}$	Turn-Off Delay Time		90			
$t_f$	Fall Time		30			
$L_D$	Internal Drain Inductance		4.5		nH	Between lead, 6 mm from package and center of die contact
$L_S$	Internal Source Inductance		7.5			
$C_{iss}$	Input Capacitance		1200		pF	$V_{GS}=0$ $V_{DS}=25\text{V}$ $f=1.0\text{MHz}$
$C_{oss}$	Output Capacitance		320			
$C_{rSS}$	Reverse Transfer Capacitance		200			

**Source-Drain Ratings and Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)			3.6	A	
$I_{SM}$	Pulsed Source Current (Body Diode) ❶			14	A	
$V_{SD}$	Diode Forward Voltage			1.8	V	$I_S=3.6\text{A}$ , $V_{GS}=0\text{V}$ , $T_J=25^\circ\text{C}$ ❹
$t_{rr}$	Reverse Recovery Time		430	650	ns	$T_J=25^\circ\text{C}$ , $I_F=3.6\text{A}$ ,❹
$Q_{rr}$	Reverse Recovery Charge		1.4	2.1	$\mu\text{C}$	$di/dt=100\text{A}/\mu\text{s}$

**Thermal resistance**

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case			1.0	W/ $^\circ\text{C}$
$R_{\theta JC}$	Case-to-Sink, Flat, Greased Surface		0.50		
$R_{\theta JC}$	Junction-to-Ambient			62	

❶ Reprtitive rating ; pulse width limited by max. junction temperature .

 ❷  $V_{DD}=50\text{V}$  , starting  $T_J=25^\circ\text{C}$  ,  $L=36\text{mH}$  ,  $R_G=25\Omega$  ,  $I_{AS}=3.6\text{A}$ .

 ❸  $I_{SD}\leq 3.6\text{A}$  ,  $di/dt\leq 70\text{A}/\mu\text{s}$  ,  $V_{DD}\leq 600\text{V}$  ,  $T_J\leq 150^\circ\text{C}$ .

 ❹ Pulse width  $\leq 300\mu\text{s}$  ; duty cycle  $\leq 2\%$